

SAMSUNG

Netlist Powered Emulation Paradigm: Pioneering Breakthroughs in Gate Level Verification

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Motivation

- Growth in Semiconductor Industry
- Rapidly increasing complexity in modern SoC designs
- Ensuring maximum verification coverage with No bug escape
- Challenge to Validate chip on time

Gate Level Simulation:

- ☐ Conventional gate level simulation is widely employed.
- ☐ High run time
- ☐ Challenge to run Full SoC GLS Simulation

Netlist Powered Emulation:

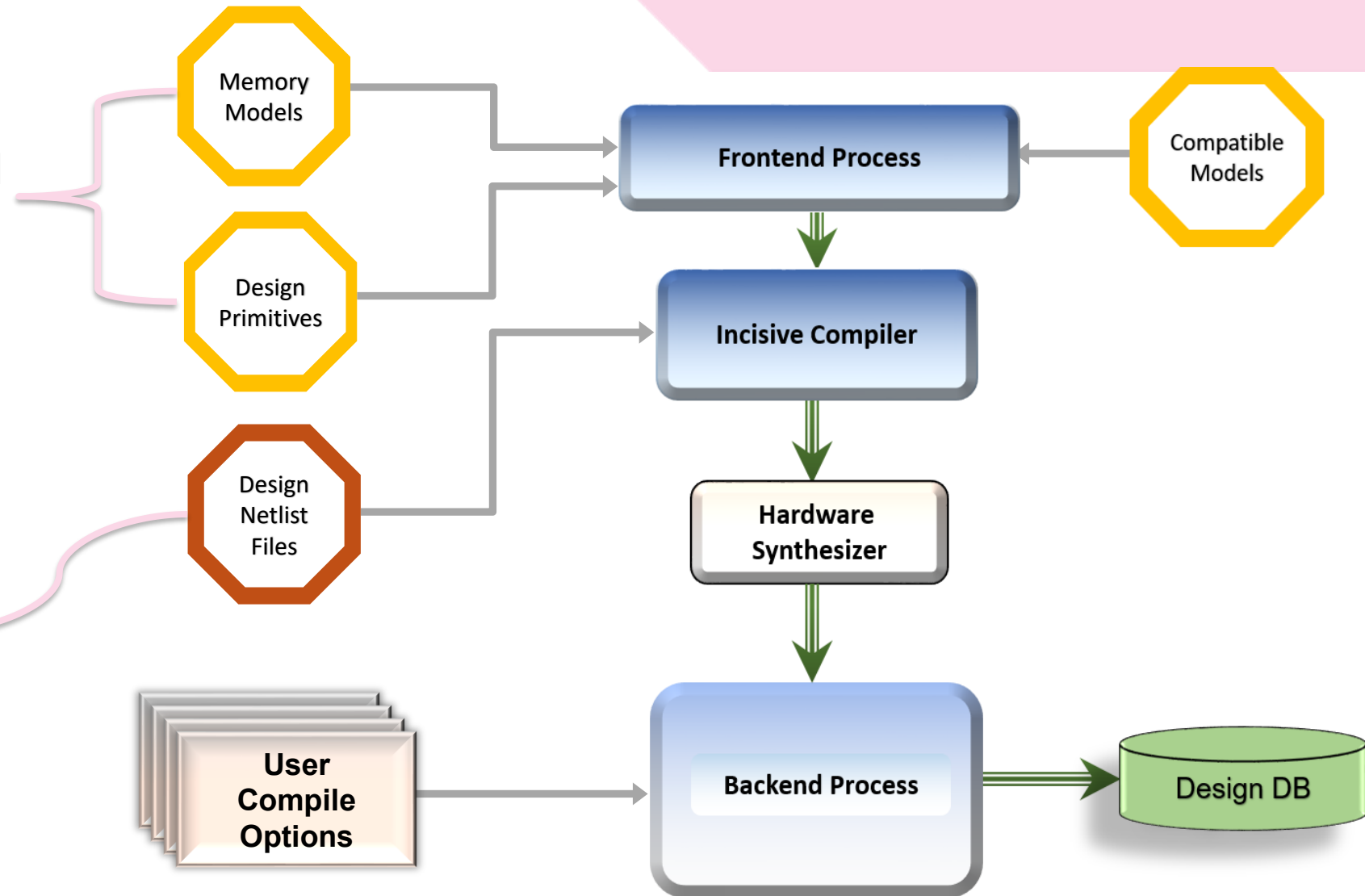
- ☐ Adopting to Zero delay netlist powered emulation
- ☐ Shorter run time
- ☐ Full SoC GLE is faster
- ☐ Execution of system level scenarios



Netlist Powered Emulation Paradigm-Methodology

All the required directive files are to be passed in the Frontend process stage for Analysis, Elaboration, Optimization

Inclusion of Netlist files at the Incisive Compiler stage by-passing the Front end process

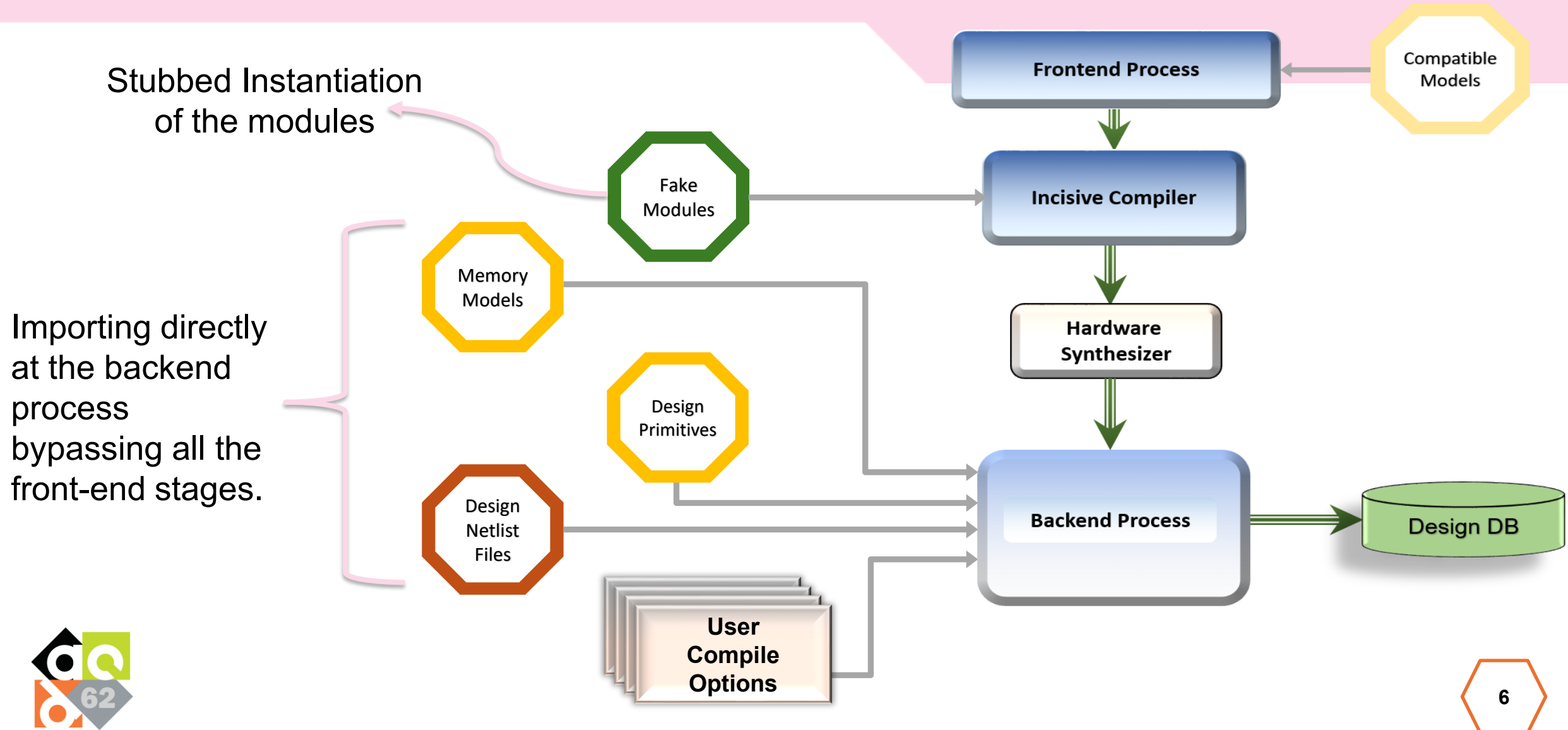


Netlist Powered Emulation Paradigm- Enhancement Techniques

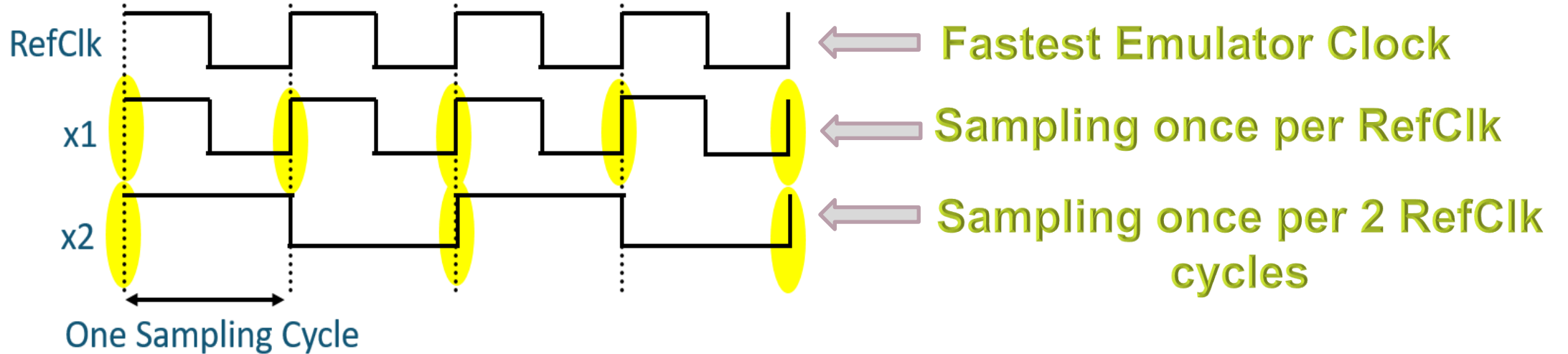
- Several Optimization strategies are proposed and devised to enhance our platform.
 - 1) Compile Time Enhancement Techniques:
Explicit Netlist Flow
 - 2) Performance Enhancement Techniques:
Oversampling Technology
Handling and Breaking Long Signal Paths
 - 3) Smarter Enhancement Techniques:
Hybrid and Stub Approach



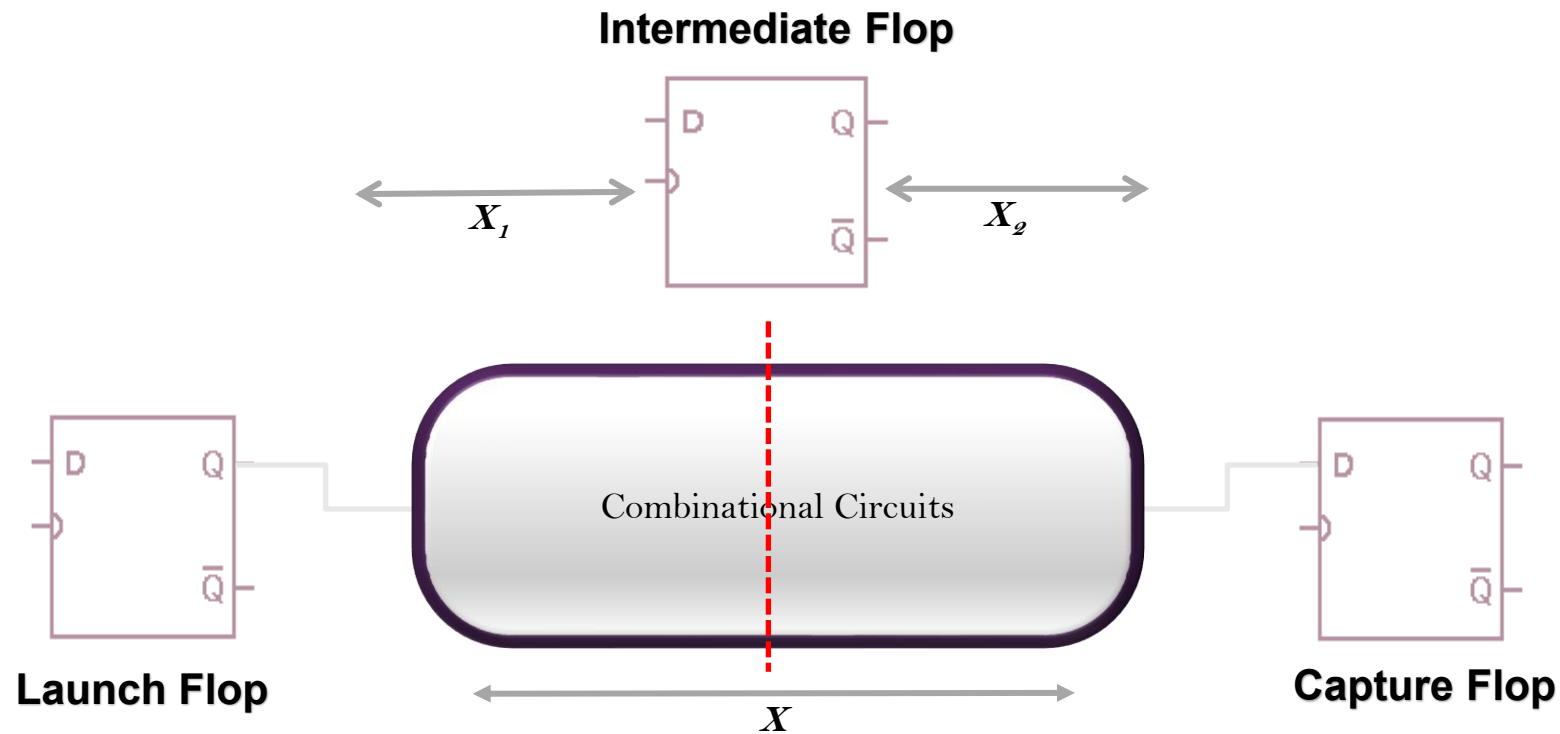
Compile Time Enhancement – Explicit Flow



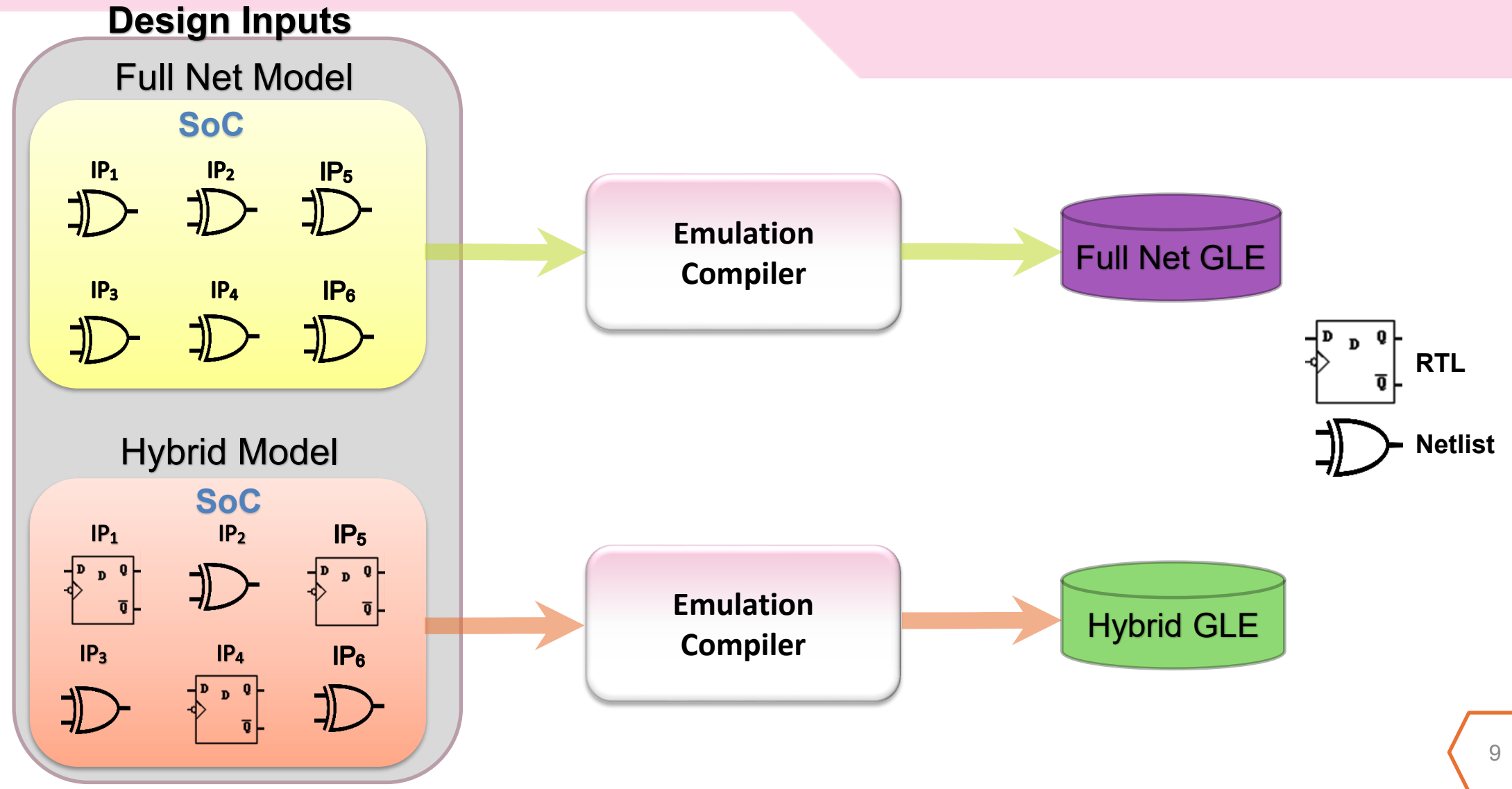
Performance Enhancement - Oversampling



Performance Enhancement – Handling Long Paths



Smarter Solutions – Hybrid GLE

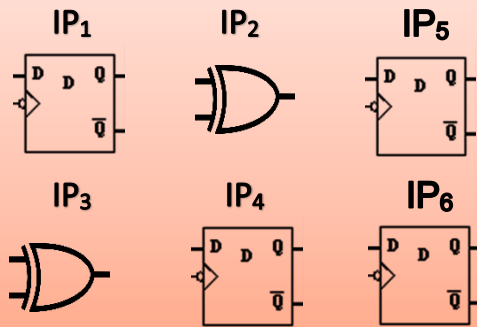


Smarter Solutions – Stubbed GLE

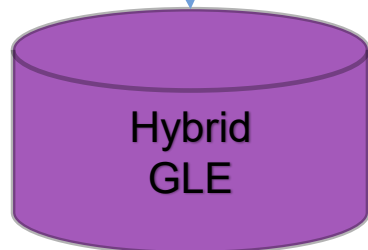
Design Inputs

Hybrid Model

SoC

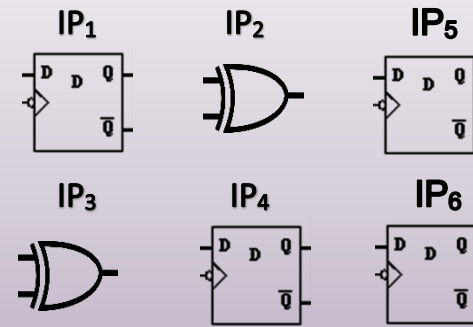


Emulation
Compiler

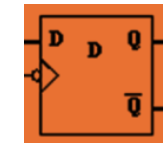
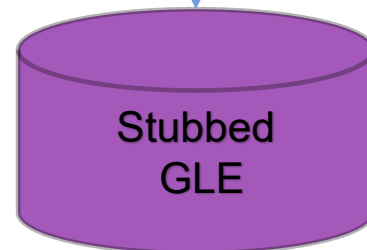


Stubbed Model

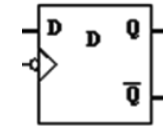
SoC



Emulation
Compiler



FAKE



RTL



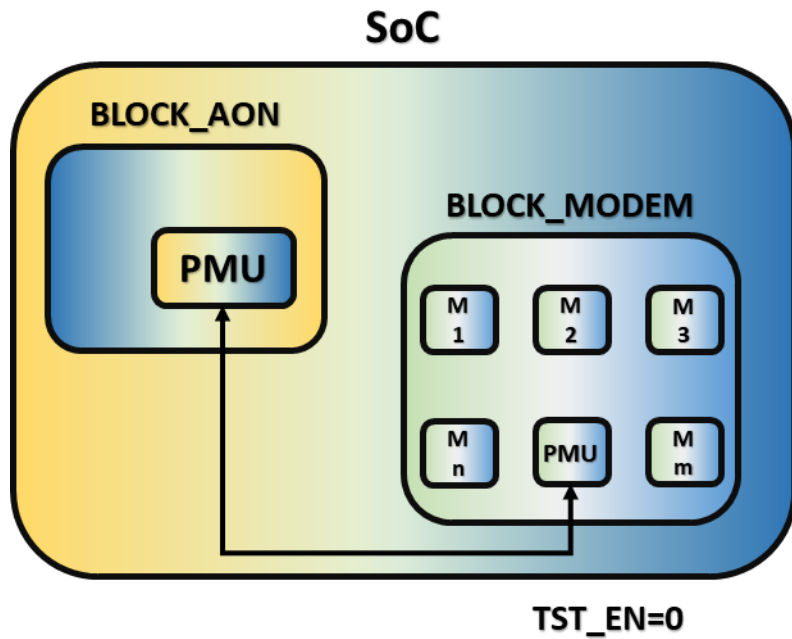
Netlist

NOTE:

1. Third party blocks are handled after thorough hardening and making them compatible to the design compiler.

Evidence/ Potential Bugs Caught

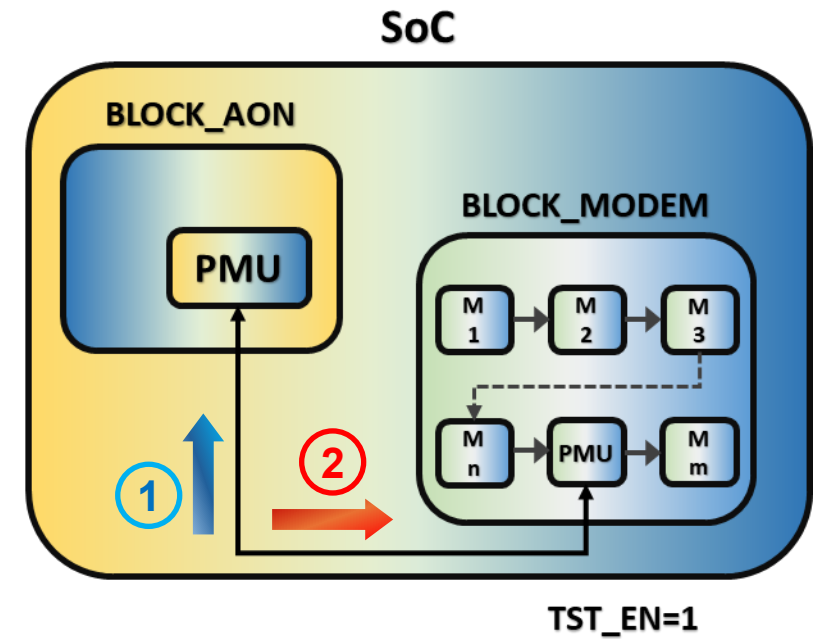
Functional Mode



Handshake between SoC PMU and BLK_MODEM PMU to ensure the modem is powered up and operates correctly



Test Mode



All IPs within the BLK_MODEM are interconnected to form a scan chain

1) During Scanning, unexpected interaction inadvertently triggers a transaction to the SoC PMU

2) SoC PMU processes transaction. Resulting in the blk_modem power down unexpectedly, disrupting its functionality

Results Summary-Compile and Run

Table I. Anticipated outcomes of verification stages on different design types and across various range of emulators

Verification Stage	Design Type	SoC (2Billion Gates)		
		GLS	FPGA	ASIC
Compile Duration (Hrs)	FULL NET	18 hrs	25 hrs	15 hrs
	Adopting Techniques	15 hrs	20 hrs	9 hrs
Operating Speed (KHz)	FULL NET	-	1400 khz	300 khz
	Adopting Techniques	-	1900 khz	700 khz

60%

45%

NOTE: Based on the application requirements, the design can be tweaked further with the smarter solutions to improve the performance and reduce the compile time



Results Summary-Run Examples

Table II. Proposed Execution Time Comparison on Gate Level Simulation vs Netlist Powered Emulation

Applications	Gate Level Simulation (Hrs)	Netlist Powered Emulation (Hrs)
SoC Boot	14	0.1
Dynamic Power Analysis	50	1.5
Scan Validation	Unrealistic	2
LBIST	Unrealistic	4

Limitations & Future Ahead ...

Limitations

- Only Zero delay/ Unit delay as timing simulation is not supported.
- When test modes are enabled, emulator driver clock drops significantly.
- Netlists have to undergo front-end process in a FPGA based compiler.

Future Ahead

- Power Aware GLE (2 State, 4 State)
- DFT scenarios Validation



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